In the Claims

- 1. (Currently Amended) An organic electroluminescent device comprising: a substrate;
- a thin film transistor formed on the substrate;
- a first electrode electrically coupled to the thin film transistor formed on the substrate;
- a <u>chemical vapor deposition</u> CVD insulating film <u>having</u> of a low dielectric constant formed on the first electrode and the substrate, the <u>chemical vapor deposition</u> CVD film having an opening portion for exposing the first electrode;

an organic electroluminescent (EL) layer formed on a base and a sidewall of the opening portion without filling the opening; and

- a second electrode formed on the organic electroluminescent EL layer.
- 2. (Currently Amended) The device as claimed in claim 1, wherein the <u>chemical</u> vapor deposition CVD insulating film <u>comprises</u> is comprised of SiOC.
- 3. (Currently Amended) The device as claimed in claim 1, wherein the <u>chemical</u> vapor deposition CVD insulating film has a dielectric constant less than about 3.5.
- 4. (Currently Amended) The device as claimed in claim 1, wherein the <u>chemical</u> <u>vapor deposition</u> CVD insulating film is formed to have a thickness more than about 1 μm.
 - 5. (Currently Amended) An The organic electroluminescent device comprising: a substrate;
- a thin film transistor formed on the substrate and having an active pattern, a gate insulating film, a gate electrode, and source/drain electrodes;
 - a passivation layer formed on the thin film transistor and the substrate;
- a pixel electrode formed on the passivation layer so as to be connected with the thin film transistor;
 - a chemical vapor deposition CVD insulating film having of a low dielectric constant

formed on the pixel electrode and the passivation layer, the <u>chemical vapor deposition</u> CVD insulating film having an opening portion for exposing the pixel electrode;

an organic <u>electroluminescent</u> EL layer formed on <u>a base and a sidewall of</u> the opening portion <u>without filling the opening portion</u>; and

a metal electrode formed on the organic <u>electroluminescent</u> <u>EL</u> layer and the <u>chemical</u> <u>vapor deposition</u> <u>CVD</u> insulating film <u>having</u> of a low dielectric constant.

- 6. (Currently Amended) The device as claimed in claim 5, wherein the <u>chemical</u> vapor deposition CVD insulating film <u>comprises</u> is comprised of SiOC.
- 7. (Currently Amended) The device as claimed in claim 5, wherein the <u>chemical</u> vapor deposition CVD insulating film has a dielectric constant less than about 3.5.
- 8. (Currently Amended) The device as claimed in claim 5, wherein the <u>chemical</u> vapor deposition CVD insulating film has a thickness more than about 1 μ m.
- 9. (Currently Amended) The device as claimed in claim 5, wherein the chemical vapor deposition CVD insulating film and an edge portion of the pixel electrode overlap each other in a width by more than about 1 μm.
 - 10. (Currently Amended) An organic electroluminescent device comprising: a substrate;
 - a thin film transistor formed on the substrate;
- a stripe-shaped first electrode <u>electrically coupled to the thin film transistor</u> formed on the substrate;
- a <u>chemical vapor deposition</u> CVD insulating film <u>having a of low dielectric constant</u> formed on the fist electrode and the substrate, the <u>chemical vapor deposition</u> CVD insulating film having an opening portion formed on the first electrode with a tapered shape;
 - an organic electroluminescent (EL) layer formed on the opening portion; and
- a stripe-shaped second electrode formed on the organic <u>electroluminescent</u> EL layer, the stripe-shaped second electrode being arranged to cross the first electrode.

- 11. (Currently Amended) The device as claimed in claim 10, wherein the <u>chemical</u> vapor deposition CVD insulating film is comprised of SiOC.
- 12. (Currently Amended) The device as claimed in claim 10, wherein the <u>chemical</u> vapor deposition CVD insulating film has a dielectric constant less than about 3.5.
- 13. (Currently Amended) The device as claimed in claim 10, wherein the chemical vapor deposition CVD insulating film has a thickness more than about 1 µm.